

## AMENDMENT UNDER 37 CFR 1.116 EXPEDITED PROCEDURE – EXAMINING GROUP 2877

**PATENT** 

Attorney Docket No.: 16869P-042900US

Client Ref. No.: 210000749US1

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Examiner:

Confirmation No. 9702

Hwa S. Lee

Technology Center/Art Unit: 2877

EXPEDITED PROCEDURE

**EXAMINING GROUP 2877** 

AMENDMENT UNDER 37 CFR 1.116

In re application of:

Takenori HIROSE, et al.

Application No.: 10/081,385

Filed: February 20, 2002

For: FILM THICKNESS MEASURING METHOD AND APPARATUS, AND THIN FILM DEVICE MANUFACTURING METHOD AND MANUFACTURING APPARATUS USING SAME

Customer No.: 20350

July 22, 2005

Mail Stop AF
Commissioner for Patents

P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In response to the Final Office Action mailed March 9, 2005 on the above-referenced application, for which a **Petition to Extend Time** for two months is enclosed, please enter the following amendments and remarks:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 3 of this paper.

Remarks/Arguments begin on page 9 of this paper.

Enclosures include a Petition under 37 CFR 1.78(a)(3) and a Statement under 37 CFR 1.78(a)(3) following page 13 of this paper.